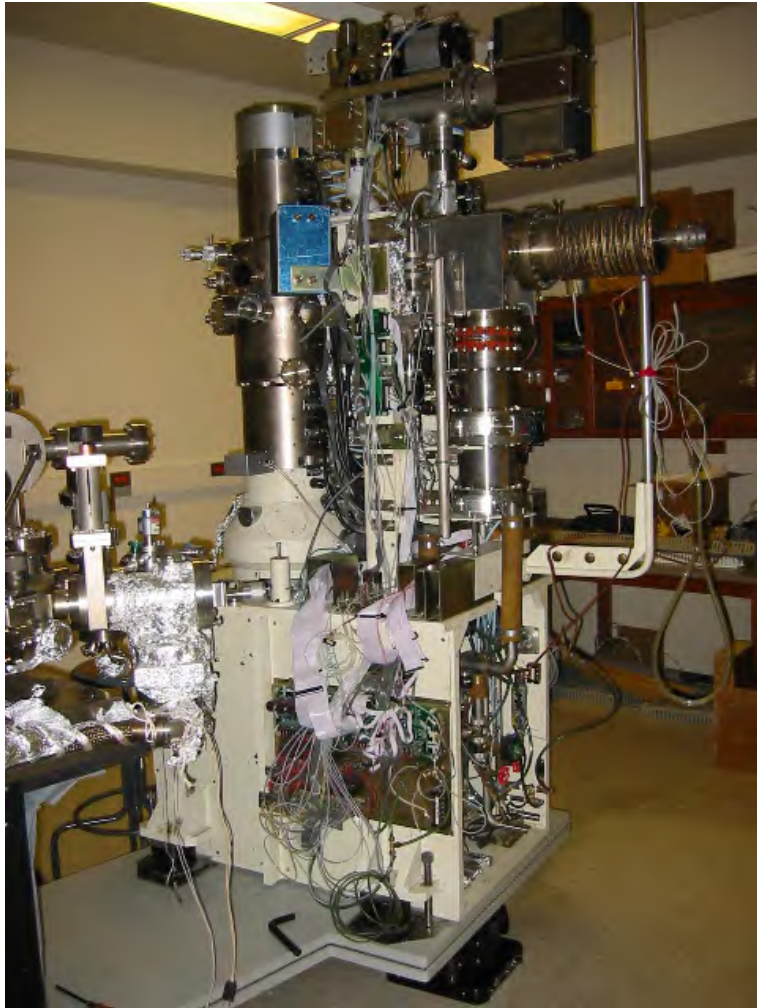
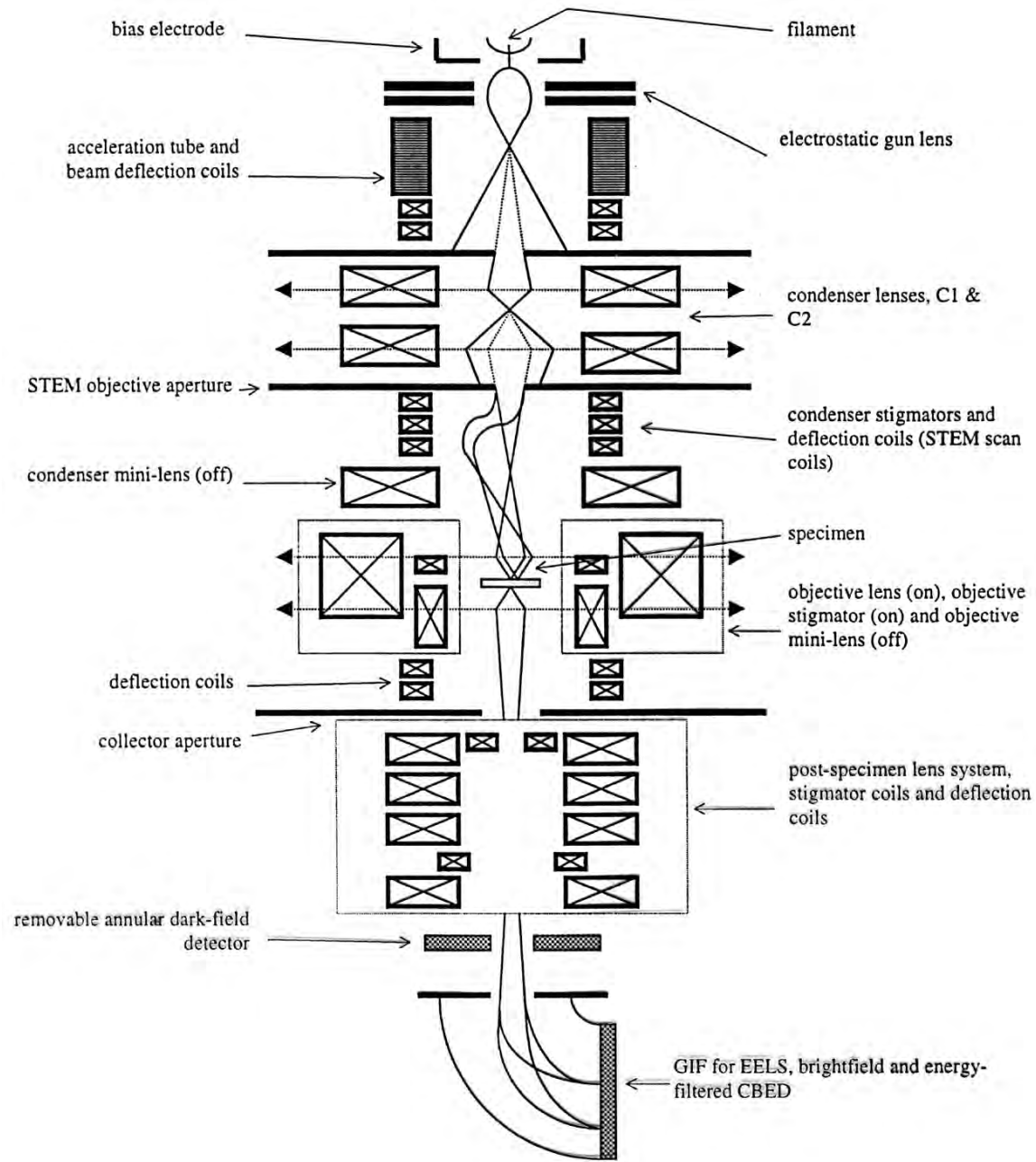


Conventional TEM



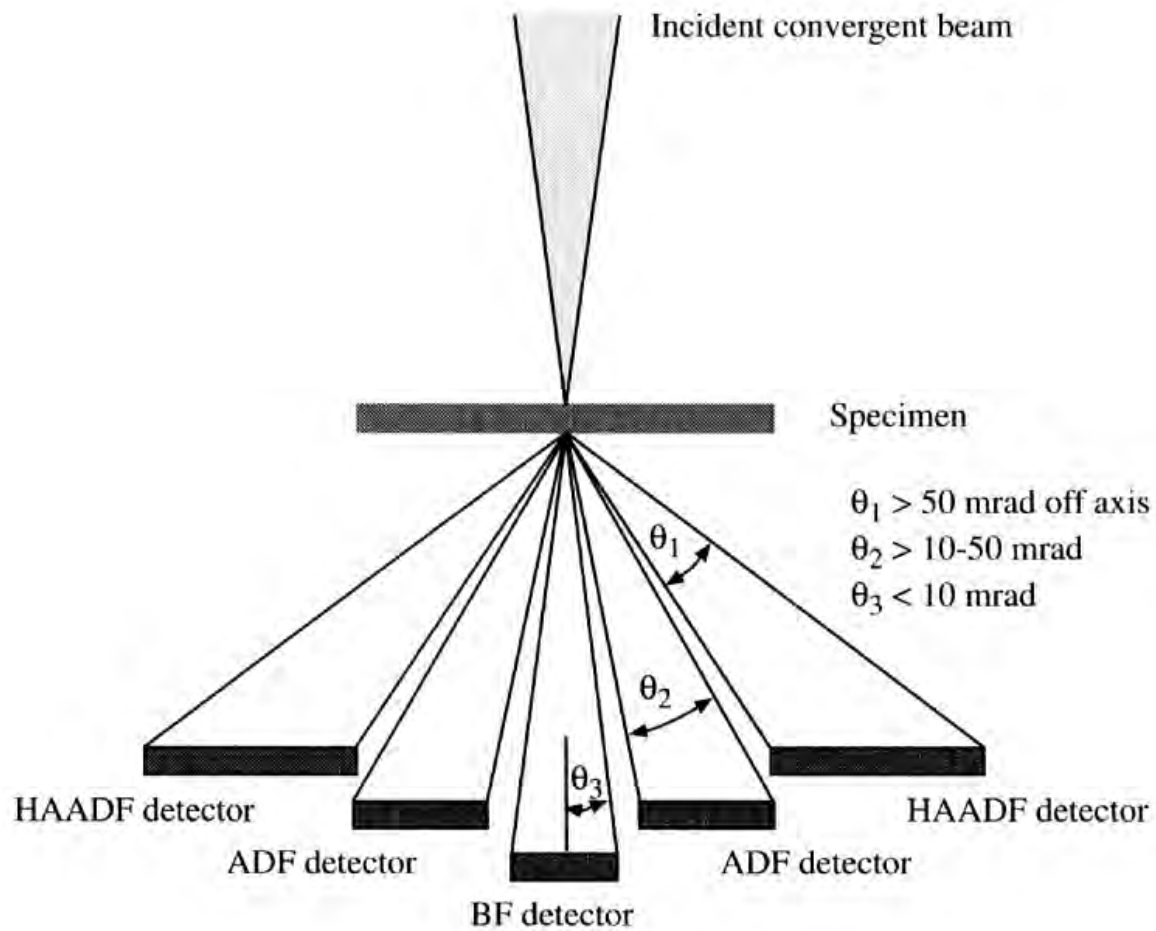
STEM



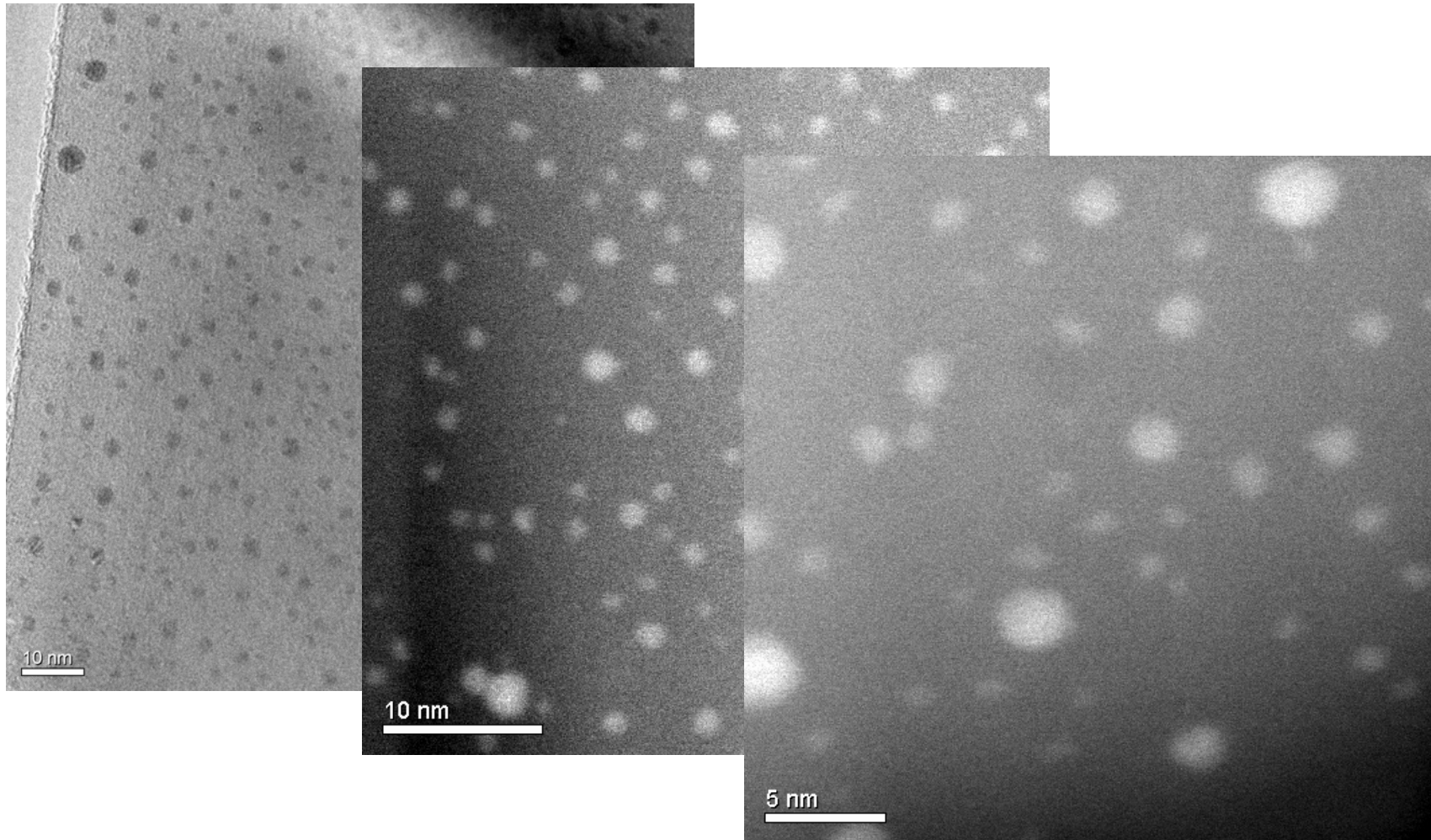


**FEG STEM
at UIC**

Z-contrast STEM Config.

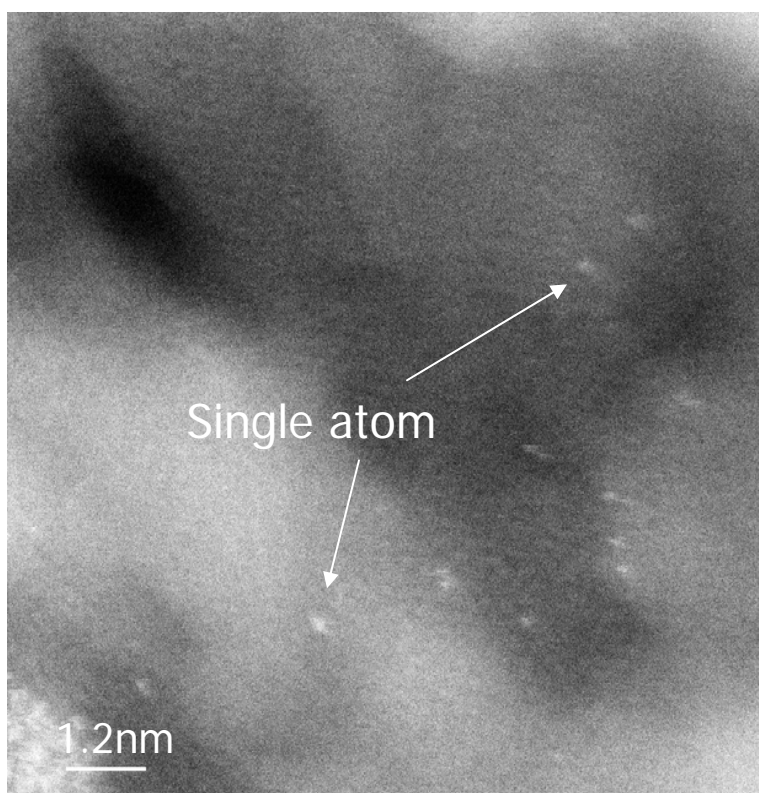


Sample H05: As-Deposit

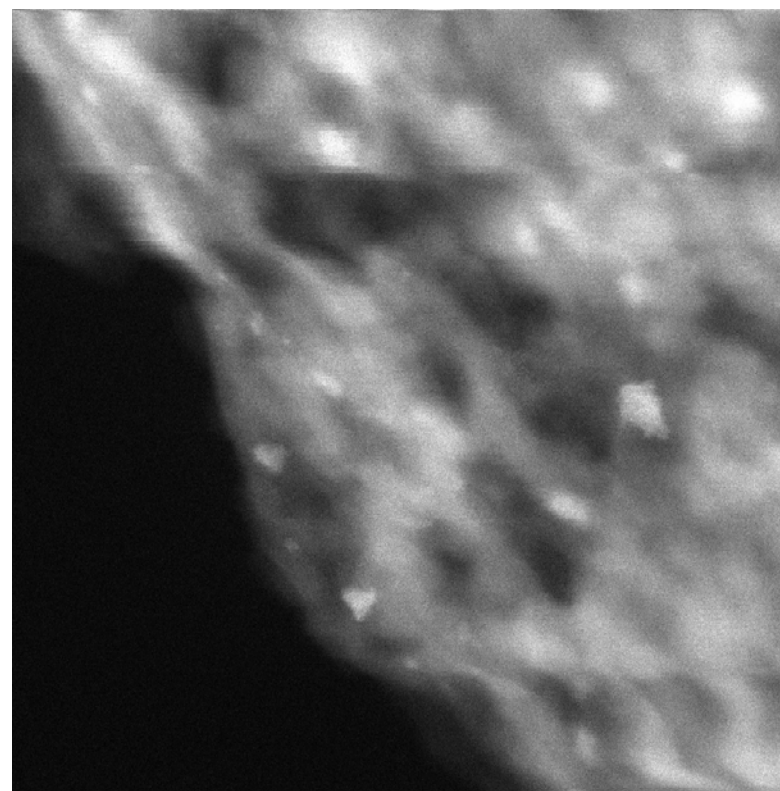


Study of Au Catalyst Structure and Morphology

Activated Au/Al₂O₃



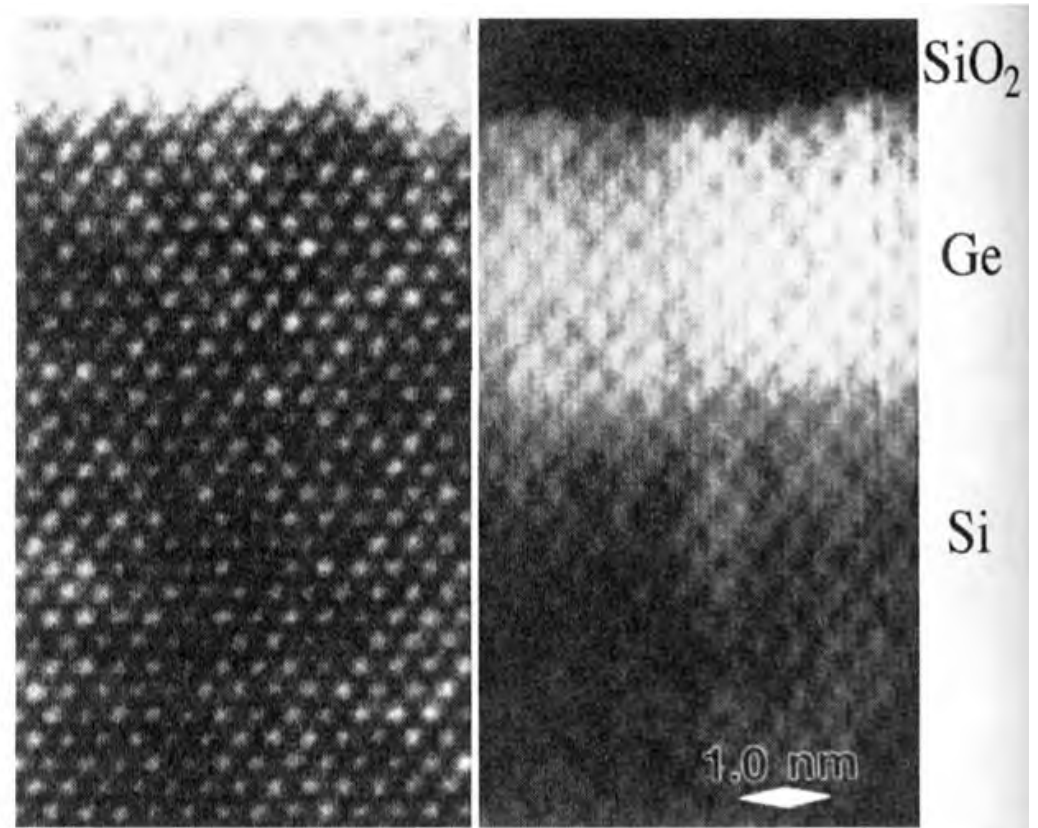
High Angle Annular Dark Field



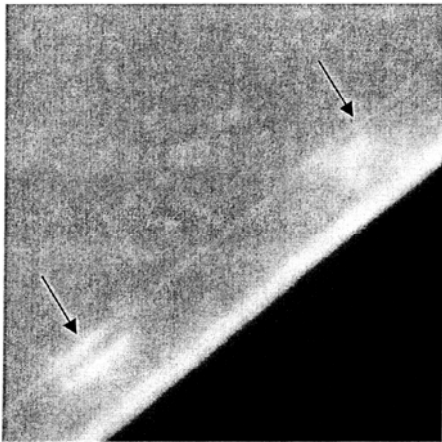
Collaborated with A. Lupini ORNL

SiO₂ on Ge on Si

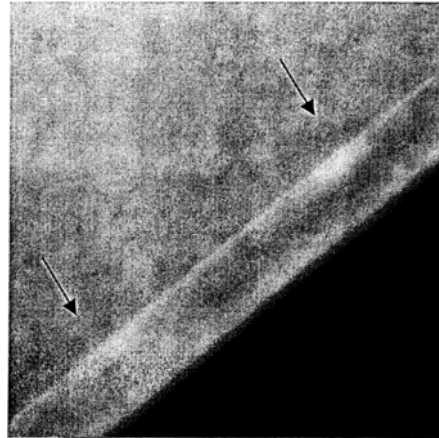
- Amorphous region is visible in hi-res
- Oxide is dark, Ge is light, Si in between - can see lattice



InGaAs quantum dots and well on GaAs



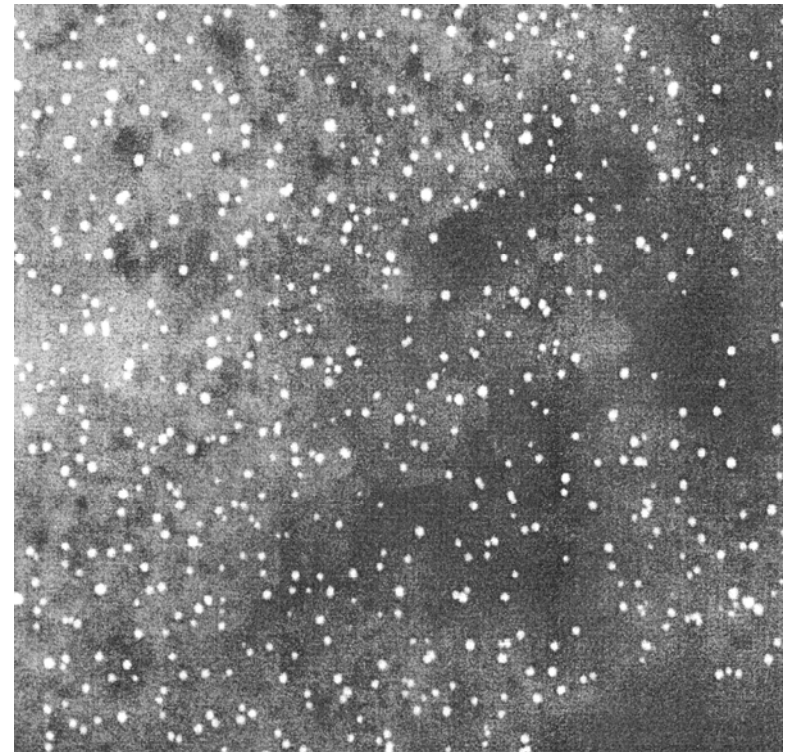
Low-angle annular dark field showing strain contrast



High-angle annular dark field showing mostly Z contrast

P. Crozier,
ASU HREM Winter
School 2003

Pt nanoparticles on carbon



P. Crozier, ASU HREM
Winter School 2003

Bi-Implanted Si

- A shows low-res BF
 - Can't really see implant
 - Can see damage
- B is Z-contrast image
 - Bi lights up like Christmas
 - The damage layer is not so visible.
 - No phase contrast

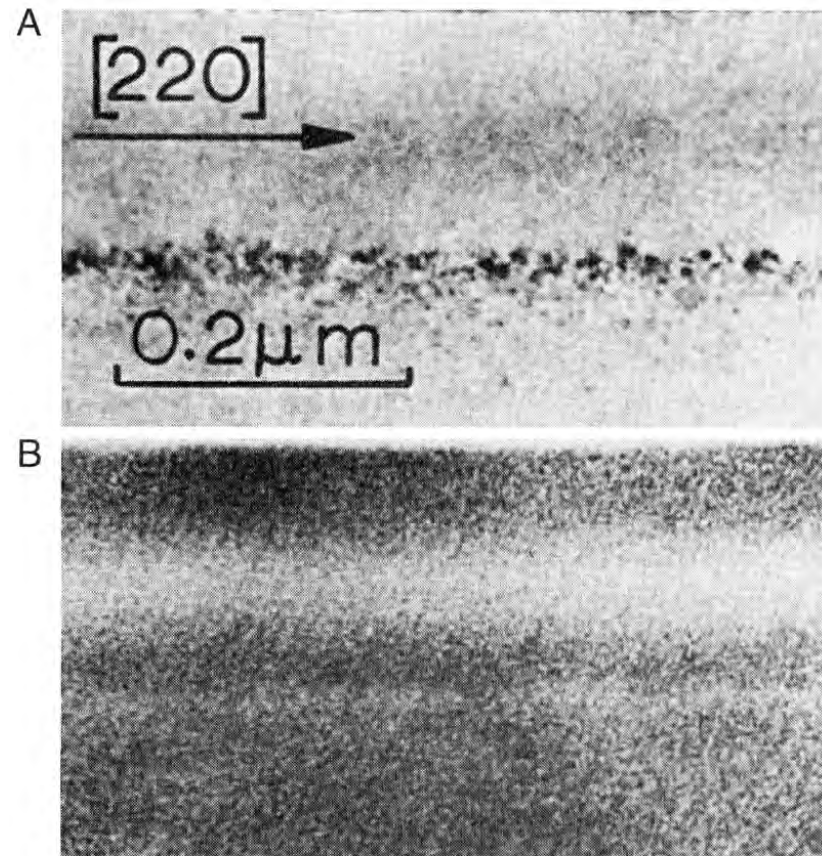
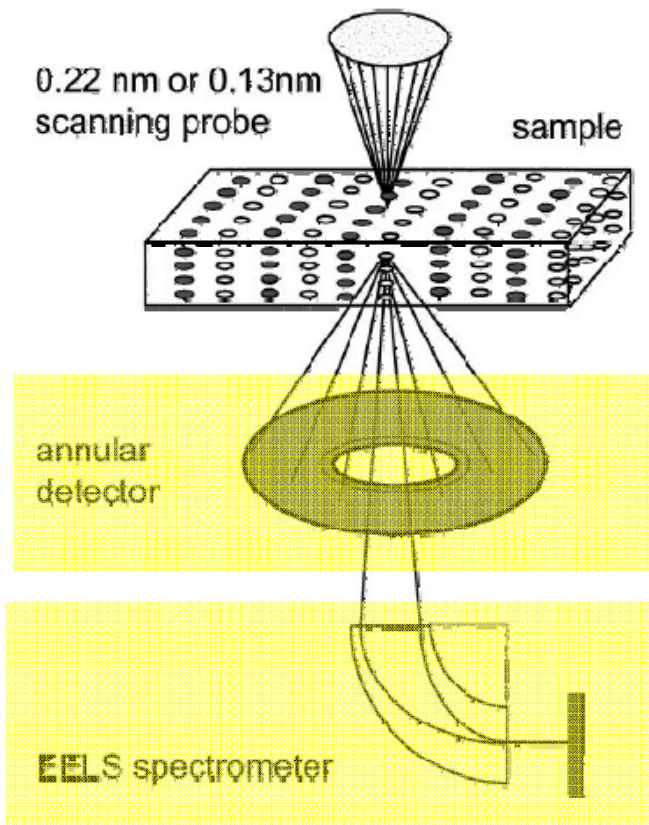


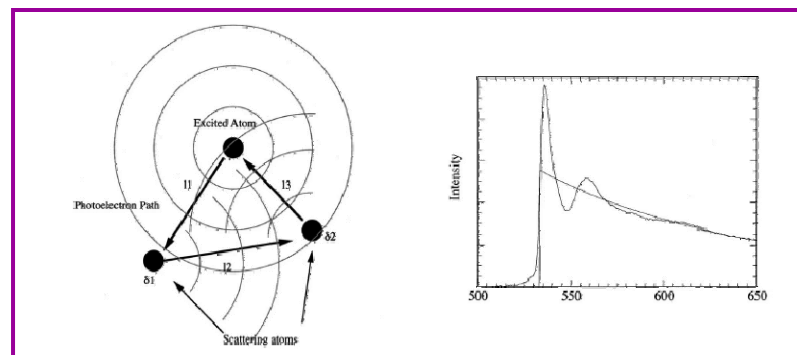
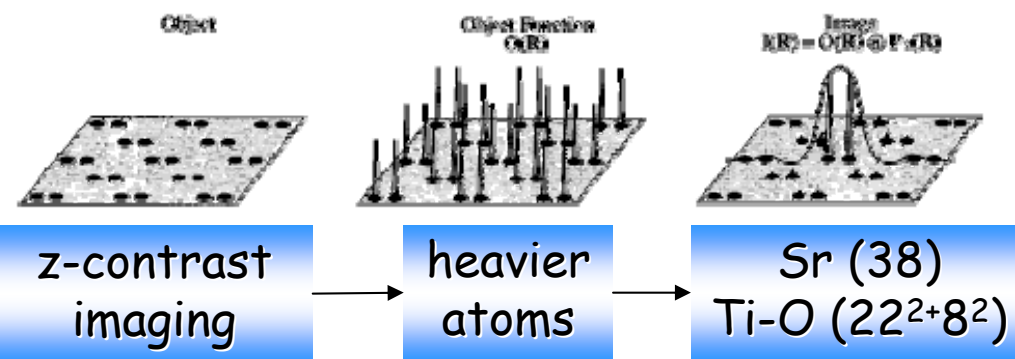
Figure 22.14. (A) Low-resolution TEM BF image showing a row of defects in Bi-implanted Si. In (B), obtained under Z-contrast conditions, the defects associated with the implant are invisible but the specimen is bright in the region implanted with Bi.

Examples borrowed from Williams & Carter

Structure model of GB in STO by z-contrast and EELS



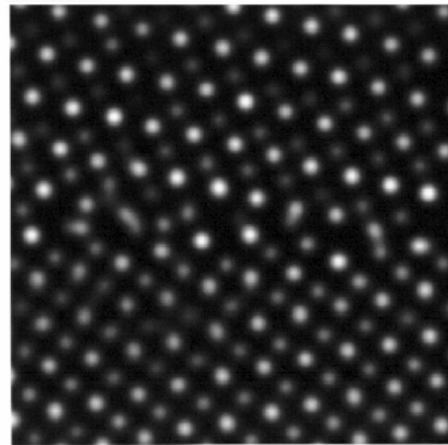
SETM



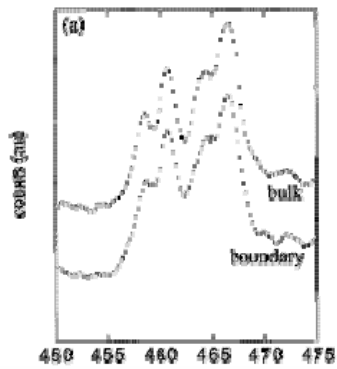
G.Duscher, J.P.Buban, N.D.Browning, M.F.Chisholm, S.J.Pennycook, *Interface science*, 2, 199 (2000)
N.D.Browning, H.O.Moltaji, J.P.Buban, *Physical review B*, 58, 8289 (1998)

STEM: VG HB501 UX

Voltage: 100kV



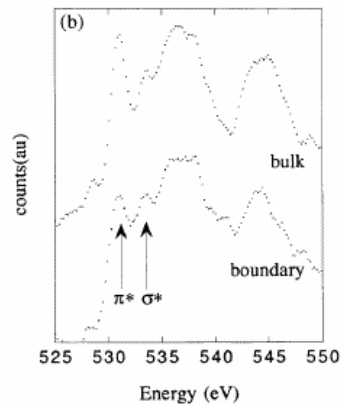
25° (920)[001]
Grain boundary



No big change

Ti atoms remain octahedrally coordinated to O atoms

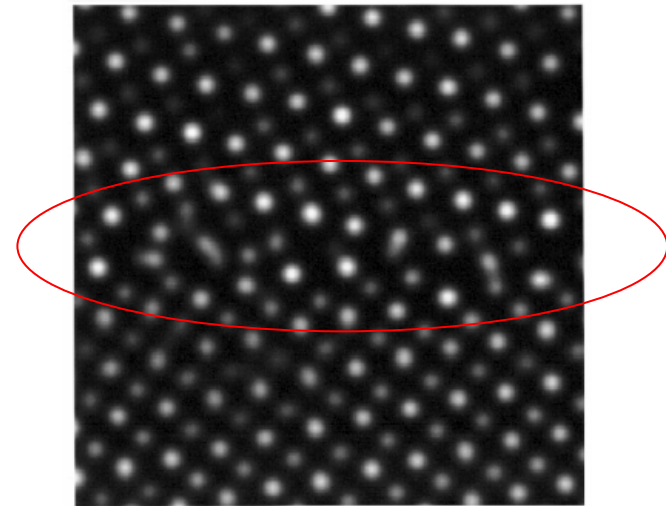
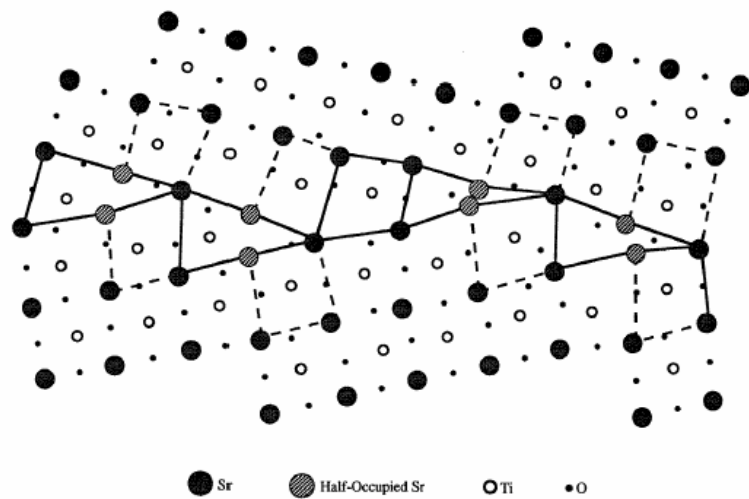
Ti is still 4+



Broadening of π^* and σ^* peaks

Increase of σ^* relative to π^*

distortion of O-Ti-O bonds



Valence	Calculated based on bulk matter	Structure unit in GB
Sr	2.11	2.11 ± 0.23
Ti	4.14	4.08 ± 0.24
O	2.08	2.08 ± 0.29